

Search Notes

Application/Control No.

10/824,824

Examiner

Brad Y. Chin

Applicant(s)/Patent under
Reexamination

SMITH ET AL.

Art Unit

1744

SEARCHED

Class	Subclass	Date	Examiner
422	5	4/22/2005	BYC
431	324	4/22/2005	BYC
431	343	4/22/2005	BYC
362	171	4/22/2005	BYC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Same	As Above	4/22/2005	BYC

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consultation with Jastrzab, Krisanne & Kim, Sun (John).	4/22/2005	BYC